

**1.0 SCOPE**

This specification covers the detail requirements for a 10-bit monolithic digital-to-analog converter which provides full-scale accuracy and high speed performance.

It is highly recommended that this data sheet be used as a baseline for new military or aerospace spec control drawings.

**1.2 Part Number.** The complete part numbers per Table I of this specification follow:

<u>Device</u>	<u>Part Number</u>	<u>Package</u>
B	DAC-10BX/883	X

**1.2.3 Case Outline.**

<u>Letter</u>	<u>Case Outline (Lead finish per MIL-M-38510)</u>
X	18-lead ceramic dual-in-line package (CERDIP)

**1.3 Absolute Maximum Ratings.** ( $T_A = 25^\circ\text{C}$ , unless otherwise noted)

Operating Temperature Range .....	$-55^\circ\text{C}$ to $+125^\circ\text{C}$
DICE Junction Temperature Range ( $T_j$ ) .....	$-65^\circ\text{C}$ to $+150^\circ\text{C}$
Storage Temperature Range .....	$-65^\circ\text{C}$ to $+150^\circ\text{C}$
Power Dissipation .....	500mW
Derate Above $100^\circ\text{C}$ .....	10mW/ $^\circ\text{C}$
Lead Temperature (Soldering, 60 sec).....	$+300^\circ\text{C}$
V+ Supply to V- Supply .....	36V
Logic Inputs.....	V- to (V- + 36V)
V <sub>LC</sub> .....	V- to V+
Analog Current Outputs .....	+18V to -18V
Reference Inputs (V <sub>16</sub> to V <sub>17</sub> ).....	V- to V+
Reference Input Differential Voltage (V <sub>16</sub> to V <sub>17</sub> ) .....	$\pm 18\text{V}$
Reference Input Current (I <sub>16</sub> ).....	2.5mA

**1.5 Thermal Characteristics:**

Thermal Resistance, CERDIP (X) package:

Junction-to-Case ( $\Theta_{JC}$ ) =  $35^\circ\text{C/W}$  MAX

Junction-to-Ambient ( $\Theta_{JA}$ ) =  $120^\circ\text{C/W}$  MAX

$V_S = \pm 15V$ ;  $I_{REF} = 2mA$ ;  $-55^\circ C \leq T_A \leq +125^\circ C$  unless otherwise specified.  
Output characteristics refer to both  $I_{OUT}$  and  $I_{OUT}$ .

Characteristics	Symbol	Special Conditions	DAC-10/883		Units
			LIMITS B		
			Min	Max	
Power Supply	I+	$V_S = \pm 15V$	-	4	mA
		$V_S = +5V, -7.5V$ ; $I_{REF} = 1mA$	-	4	mA
	I-	$V_S = \pm 15V$	-	-15	mA
		$V_S = +5V, -7.5V$ ; $I_{REF} = 1mA$	-	-9	mA
Full-Scale Current	$I_{FR}$	$V_{REF} = 10.000V$ $R_{16}, R_{17} = 5.000k\Omega$	3.960	4.032	mA
		$V_{REF} = 10.000V$ $R_{16}, R_{17} = 5.000k\Omega$ $T_A = +25^\circ C$	3.978	4.014	mA
Output Voltage Compliance	$V_{OC}$	Full-Scale Current Change < 1 LSB, $T_A = +25^\circ C$	-5	10	V
Power Supply Sensitivity	$PSSI_{FS+}$	$V+ = +4.5$ to $+18V$ ; $V- = -18V$	-	$\pm 0.01$	$\frac{\% \Delta I_{FS}}{\% \Delta V+}$
	$PSSI_{FS-}$	$V- = -10$ to $-18V$ ; $V+ = +18V$	-	$\pm 0.01$	$\frac{\% \Delta I_{FS}}{\% \Delta V-}$
Logic Input Levels	$V_{IL}$	Logic "0", $V_{LC} = 0V$	-	0.8	V
	$V_{IH}$	Logic "1", $V_{LC} = 0V$	2.0	-	V
Logic Input Current (Each Bit)	$I_{IL}$	$V_{IN} = -5V, V_{LC} = 0V$	-	-10	$\mu A$
	$I_{IH}$	$V_{IN} = 18V, V_{LC} = 0V$	-	10	$\mu A$
Zero-Scale Current	$I_{ZS}$		-	$\pm 0.5$	$\mu A$
Full-Scale Symmetry	$I_{FSS}$	$ I_{FR} - \overline{I_{FR}} $	-	4.0	$\mu A$
Monotonicity			10	-	Bits

**TABLE 1 (Continued)**

$V_S = \pm 15V$ ;  $I_{REF} = 2mA$ ;  $-55^\circ C \leq T_A \leq +125^\circ C$  unless otherwise specified.  
Output characteristics refer to both  $I_{OUT}$  and  $I_{OUT}$ .

Characteristics	Symbol	Special Conditions	DAC-10/883		Units
			LIMITS B		
			Min	Max	
Nonlinearity	NL		--	$\pm 1/2$	LSB
Settling Time	$t_s$	All Bits Switched On or Off, Settle to 0.05% of FS $T_A = +25^\circ C$	--	165	ns
Differential Nonlinearity	DNL		--	$\pm 1$	LSB
Power Dissipation (Note 1)	$P_d$	$V_S = \pm 15V$	--	285	mW
		$V_S = +5V, -7.5V$ ; $I_{REF} = 1mA$	--	88	mW
Reference Bias Current	$I_B$		--	-3.0	$\mu A$

## NOTES:

1. Power dissipation ( $P_d$ ) limits are guaranteed by supply current testing.

**DAC-10/883****Electrical Test Requirements  
For Class B Devices**

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<b>MIL-STD-883 Test Requirements</b>	<b>Subgroups (see Table 3)</b>
<b>Interim Electrical Parameters (pre Burn-In)</b>	<b>1</b>
<b>Final Electrical Test Parameters</b>	<b>1*, 2, 3</b>
<b>Group A Test Requirements</b>	<b>1, 2, 3</b>

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\* PDA applies to Subgroup 1 only.  
No other Subgroups are included in PDA.

## Group A Inspection

$V_S = \pm 15V$ ;  $I_{REF} = 2mA$  unless otherwise specified.  
Output characteristics refer to both  $I_{OUT}$  and  $I_{OUT}$ .

Subgroup	Symbol	Special Conditions	LIMITS B		Units
			Min	Max	
Subgroup 1	I+	$V_S = \pm 15V$	-	4	mA
		$V_S = +5V, -7.5V$ ; $I_{REF} = 1mA$	-	4	mA
$T_A = +25^\circ C$	I-	$V_S = \pm 15V$	-	-15	mA
		$V_S = +5V, -7.5V$ ; $I_{REF} = 1mA$	-	-9	mA
	$I_{FR}$	$V_{REF} = 10.000V$ $R_{16}, R_{17} = 5.000k\Omega$	3.978	4.014	mA
	$V_{OC}$	Full-Scale Current Change < 1 LSB	-5	10	V
	$I_{ZS}$		-	$\pm 0.5$	$\mu A$
	$I_{FSS}$	$ I_{FR} - \overline{I_{FR}} $	-	4	$\mu A$
	$PSSI_{FS+}$	$V+ = 4.5, 18V$ $V- = -18V$	-	$\pm 0.01$	$\frac{\% \Delta I_{FS}}{\% \Delta V+}$
	$PSSI_{FS-}$	$V- = -10, -18V$ $V+ = 18V$	-	$\pm 0.01$	$\frac{\% \Delta I_{FS}}{\% \Delta V-}$
	$V_{IL}$	Logic "0", $V_{LC} = 0V$	-	0.8	V
	$V_{IH}$	Logic "1", $V_{LC} = 0V$	2	-	V
	$I_{IL}$	$V_{IN} = -5V, V_{LC} = 0V$	-	-10	$\mu A$
	$I_{IH}$	$V_{IN} = +18V, V_{LC} = 0V$	-	10	$\mu A$
	Monotonicity		10	-	Bits
	NL		-	$\pm 1/2$	LSB

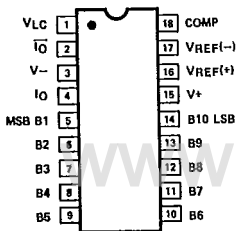
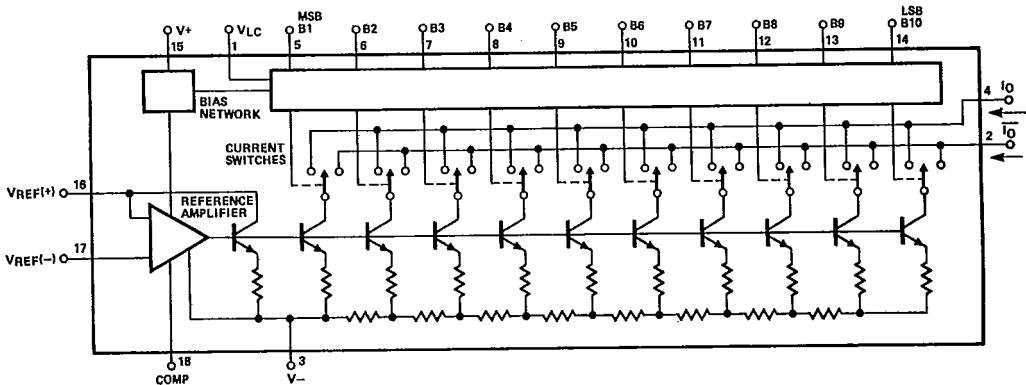
**TABLE 3****Group A Inspection (Continued)**

$V_S = \pm 15V$ ;  $I_{REF} = 2mA$  unless otherwise specified.  
Output characteristics refer to both  $I_{OUT}$  and  $I_{OUT}$ .

Subgroup	Symbol	Special Conditions	DAC-10/883		Units
			LIMITS B		
			Min	Max	
Subgroup 1	DNL		-	$\pm 1$	LSB
$T_A = +25^\circ C$	$I_B$		-	-3.0	$\mu A$
(Continued)	$P_d$ (Note 1)	$V_S = \pm 15V$ $V_S = +5V, -7.5V$ ; $I_{REF} = 1mA$	-	285	mW
			-	88	mW
Subgroup 2	$I_{FR}$	$V_{REF} = 10.000V$ $R_{16}, R_{17} = 5.000k\Omega$	3.960	4.032	mA
$T_A = +125^\circ C$		Remaining Tests, Limits and Conditions are the same as for Subgroup 1 excluding $V_{OC}$ .			
Subgroup 3		All Tests, Limits and Conditions are the same as for Subgroup 2.			
$T_A = -55^\circ C$					

**NOTES:**

1. Power dissipation ( $P_d$ ) limits are guaranteed by supply current testing.



**18-PIN HERMETIC DIP (X-Suffix)**

**3.2.4 Microcircuit Group Assignment.** This microcircuit is covered by microcircuit group 56.

**4.2 Life Test/Burn-In Circuit.**

